

Multi-Site Cost/Benefit Analysis

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Agenda

- Purpose
- Description of Cost Model
- Discuss Cost Variables
 - Drivers
 - Multi-site inefficiencies
- Summary

Purpose

- Cost modeling for multi-site decision performed by most, but analysis typically simple
- Provide simple but comprehensive model to facilitate decision process
- An hour of analysis can have significant cost impact

Run Your Numbers!

Cost Model

Wafer/Test Data

Single Site Sort

Dual Site Sort

Wafer Volume

TD's/Wafer

TD's/Wafer

Total Sort Time

PC's needed

TD Efficiency

Test Cell Cost

PH rebuilds

TT Efficiency

Total Volume Test Cost

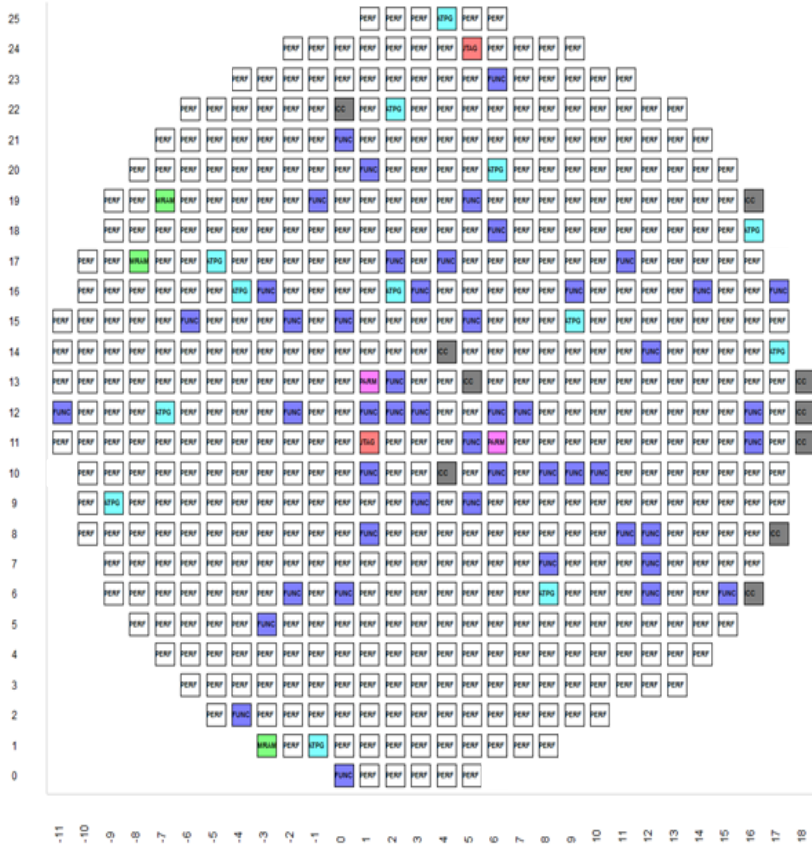
Yield Efficiency

PC's needed

PH rebuilds

Total Volume Test Cost

Base Data for Cost Analysis



- 592 die per wafer
- 3000 contacts/DUT
- Test Time
 - Two Sort Steps, 10s each
- Pure digital test
- Base Test Cell Cost
\$50/hr
- \$30K NRE for Dual Site

Bigger is Better!

Delta Test Cell Cost		Total Program Wafer Volume							
		500	1,000	1,500	2,000	2,500	3,000	3,500	4,000
\$	-	\$ 51	\$ 125	\$ 200	\$ 274	\$ 349	\$ 409	\$ 484	\$ 575
\$	5.00	\$ 39	\$ 103	\$ 166	\$ 230	\$ 293	\$ 342	\$ 405	\$ 485
\$	10.00	\$ 28	\$ 80	\$ 133	\$ 185	\$ 237	\$ 275	\$ 327	\$ 396
\$	15.00	\$ 17	\$ 58	\$ 99	\$ 140	\$ 181	\$ 208	\$ 249	\$ 306
\$	20.00	\$ 6	\$ 36	\$ 66	\$ 95	\$ 125	\$ 140	\$ 170	\$ 217
\$	25.00	\$ (5)	\$ 13	\$ 32	\$ 51	\$ 69	\$ 73	\$ 92	\$ 127
\$	30.00	\$ (17)	\$ (9)	\$ (2)	\$ 6	\$ 13	\$ 6	\$ 14	\$ 38

Thousands

- No Dual-site inefficiencies
- Model dominated by pure reduced wafer test cost
- Probe card price + NRE only a factor at low volume and at higher dual site test cell cost

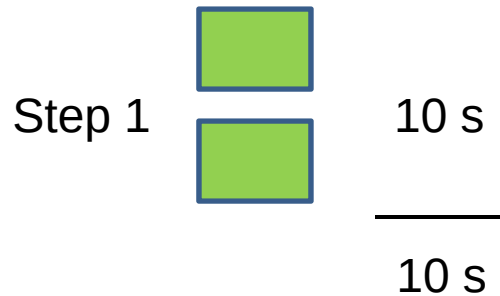
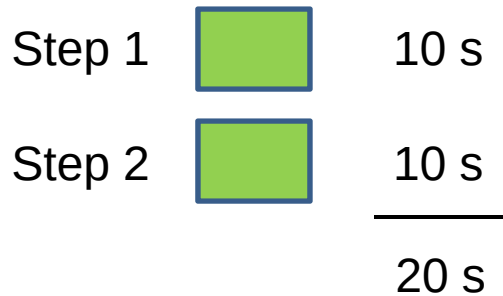
Multi-site Inefficiencies - Tester

Delta Test Cell Cost		Wafer Volume							
		500	1,000	1,500	2,000	2,500	3,000	3,500	4,000
\$	-	\$ 51	\$ 125	\$ 200	\$ 274	\$ 349	\$ 409	\$ 484	\$ 575
\$	5.00	\$ 39	\$ 103	\$ 166	\$ 230	\$ 293	\$ 342	\$ 405	\$ 485
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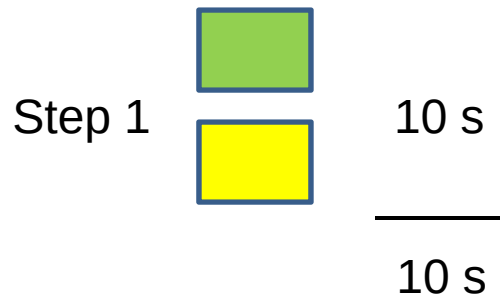
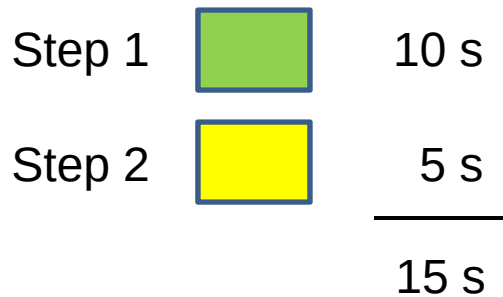
Thousands

- Inefficiency
 - CPU, Data Handling, Analog Resources
 - Test Resources
- Assume 5% dual site efficiency test time hit

Multi-site Inefficiencies - Yield

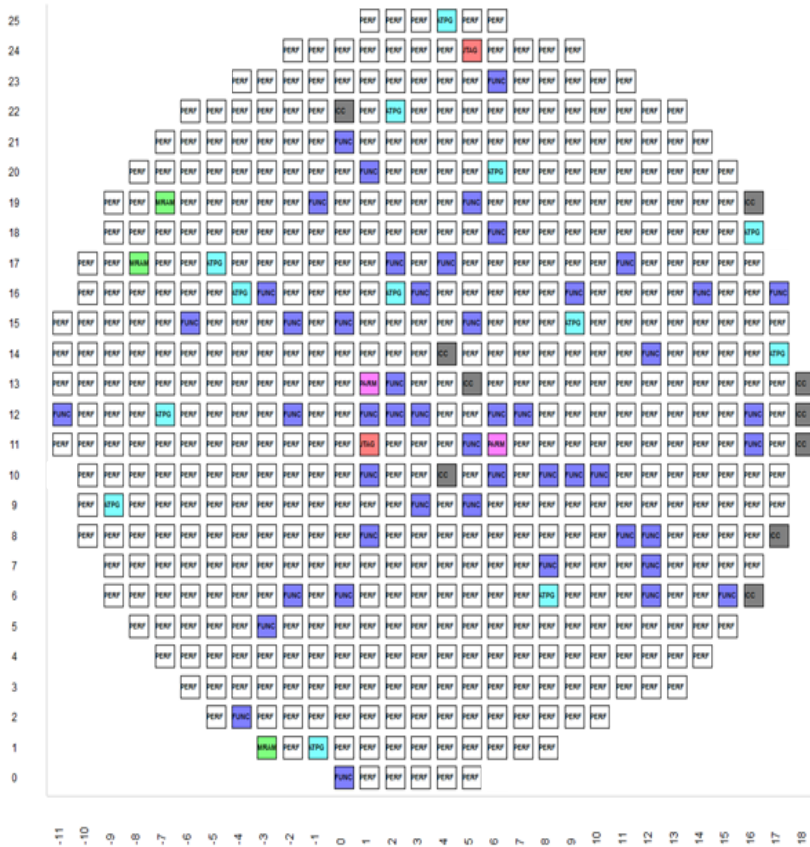


100% Efficient!



67% Efficient...

Multi-site Inefficiencies - Yield



Result	Percent	Total Test Time (s)
Good	86.8%	5140
Fail	13.2%	390

Total Test Time Single Site **5530**

Good/Good	75.4%	2262
Good/Bad	22.8%	686
Bad/Bad	1.7%	26

Total Test Time Dual Site **2974**

592 dpw
514 Pass – 86.8%
79 Fail

$$\frac{(5530/2)}{2974} = 93.0\%$$

- Model predicts 88.2% Yield Impact

[illegible]

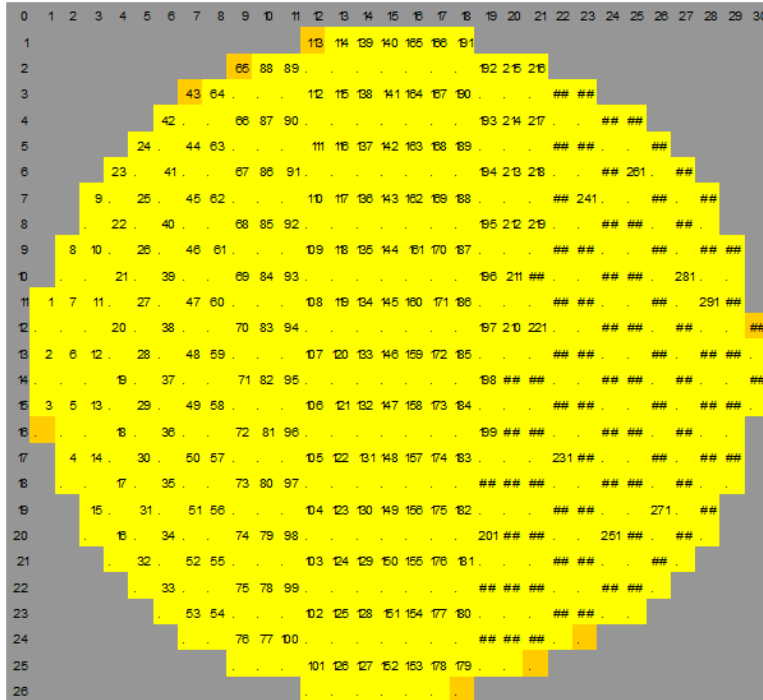
Multi-site Inefficiencies - Yield

		500	1,000	1,500	2,000	2,500	3,000	3,500	4,000
\$	-	\$ (4)	\$ 61	\$ 125	\$ 190	\$ 255	\$ 336	\$ 401	\$ 483
\$	5.00	\$ (17)	\$ 35	\$ 87	\$ 139	\$ 192	\$ 260	\$ 313	\$ 381
\$	10.00	\$ (30)	\$ 10	\$ 49	\$ 89	\$ 128	\$ 184	\$ 224	\$ 280
\$	15.00	\$ (42)	\$ (15)	\$ 11	\$ 38	\$ 65	\$ 108	\$ 135	\$ 179
\$	20.00	\$ (55)	\$ (41)	\$ (27)	\$ (13)	\$ 2	\$ 32	\$ 47	\$ 77
\$	25.00	\$ (68)	\$ (66)	\$ (65)	\$ (63)	\$ (62)	\$ (44)	\$ (42)	\$ (24)
\$	30.00	\$ (80)	\$ (91)	\$ (103)	\$ (114)	\$ (125)	\$ (120)	\$ (131)	\$ (125)

Thousands

- Wafer Yield 86.8% equals inefficiency of 93%

Multi-site Inefficiencies - Stepping



- Multi-site Arrays typically not 100% efficient
 - Theoretical best stepping on 592 wafer would be 296 steps
 - This wafer requires 300 steps – 98.8% efficient

Multi-site Inefficiencies - Stepping

		<i>Wafer Volume</i>							
		500	1,000	1,500	2,000	2,500	3,000	3,500	4,000
\$	-	\$ (4)	\$ 61	\$ 125	\$ 190	\$ 255	\$ 336	\$ 401	\$ 483
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\$	30.00	\$ (80)	\$ (91)	\$ (103)	\$ (114)	\$ (125)	\$ (120)	\$ (131)	\$ (125)

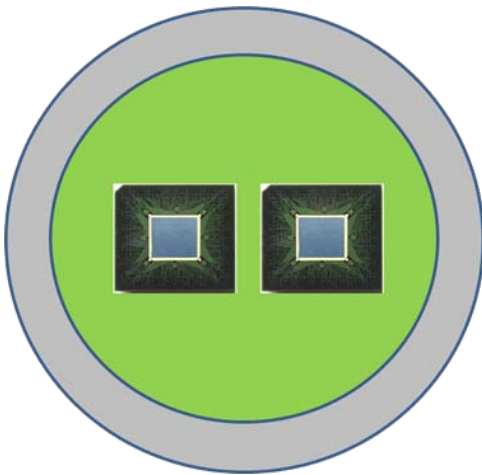
Thousands

- Effect of 98.8% Stepping Efficiency
- NRE buys best Stepping, but can it be reduced?

Strategies to Reduce PC NRE

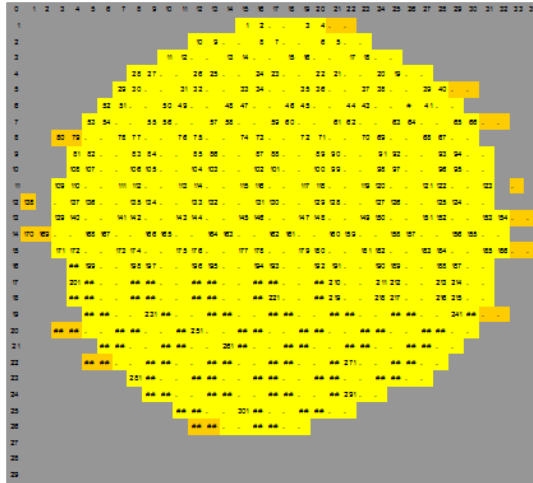


- Dual site MLO based on device package

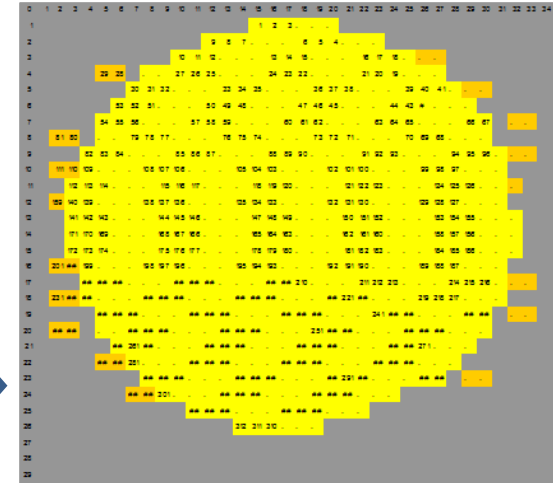


- Two final MLO packages attached to Probe Card PCB

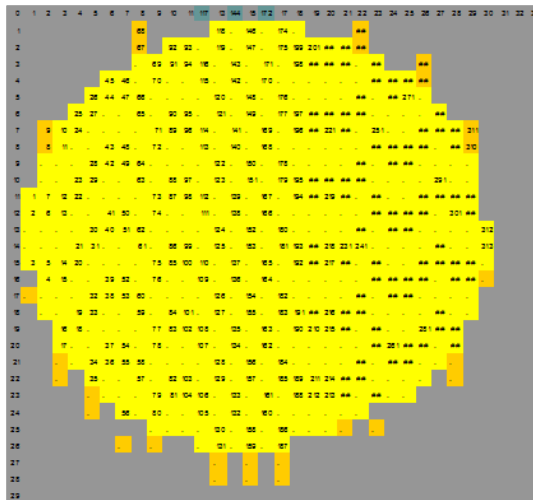
Stepping Efficiency Analysis



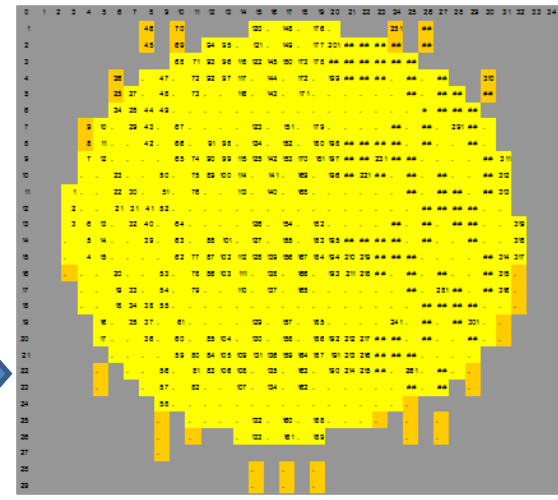
2x1 S1C
308 TDs
95.9%



2x1 S2C
312 TDs
94.6%



1x2 S1R
313 TDs
94.3%



1x2 S2R
319 TDs
92.2%

Effect of Skips

Wafer Volume

		500	1000	1500	2000	2500	3000	3500	4000	
\$	-	\$ (5)	\$ 58	\$ 122	\$ 186	\$ 249	\$ 330	\$ 393	\$ 474	
\$	7.50	\$ (18)	\$ 33	\$ 83	\$ 134	\$ 185	\$ 253	\$ 303	\$ 371	
\$	15.00	\$ (31)	\$ 7	\$ 45	\$ 83	\$ 121	\$ 176	\$ 214	\$ 268	
\$	22.50	\$ (44)	\$ (19)	\$ 6	\$ 31	\$ 57	\$ 99	\$ 124	\$ 166	Solid 1x2
\$	30.00	\$ (57)	\$ (44)	\$ (32)	\$ (20)	\$ (8)	\$ 21	\$ 34	\$ 63	98.8% efficient
\$	37.50	\$ (70)	\$ (70)	\$ (71)	\$ (71)	\$ (72)	\$ (56)	\$ (56)	\$ (40)	Includes \$30K NRE
\$	45.00	\$ (82)	\$ (96)	\$ (109)	\$ (123)	\$ (136)	\$ (133)	\$ (146)	\$ (143)	
		500	1000	1500	2000	2500	3000	3500	4000	
\$	-	\$ 18	\$ 76	\$ 133	\$ 190	\$ 248	\$ 322	\$ 379	\$ 422	
\$	7.50	\$ 5	\$ 48	\$ 92	\$ 135	\$ 179	\$ 239	\$ 283	\$ 312	
\$	15.00	\$ (9)	\$ 21	\$ 50	\$ 80	\$ 110	\$ 157	\$ 186	\$ 201	
\$	22.50	\$ (23)	\$ (7)	\$ 9	\$ 25	\$ 41	\$ 74	\$ 90	\$ 91	2x1 S2R
\$	30.00	\$ (37)	\$ (35)	\$ (32)	\$ (30)	\$ (28)	\$ (9)	\$ (7)	\$ (19)	92.2% efficient
\$	37.50	\$ (51)	\$ (62)	\$ (74)	\$ (85)	\$ (97)	\$ (91)	\$ (103)	\$ (129)	No NRE
\$	45.00	\$ (64)	\$ (90)	\$ (115)	\$ (140)	\$ (166)	\$ (174)	\$ (199)	\$ (240)	
\$		\$ 24	\$ 17	\$ 11	\$ 5	\$ (1)	\$ (8)	\$ (14)	\$ (52)	
\$		\$ 23	\$ 16	\$ 8	\$ 1	\$ (6)	\$ (13)	\$ (21)	\$ (59)	
\$		\$ 22	\$ 14	\$ 6	\$ (3)	\$ (11)	\$ (19)	\$ (27)	\$ (67)	
\$		\$ 21	\$ 12	\$ 3	\$ (6)	\$ (16)	\$ (25)	\$ (34)	\$ (74)	
\$		\$ 20	\$ 10	\$ (0)	\$ (10)	\$ (20)	\$ (30)	\$ (40)	\$ (82)	
\$		\$ 19	\$ 8	\$ (3)	\$ (14)	\$ (25)	\$ (36)	\$ (47)	\$ (89)	
\$		\$ 18	\$ 6	\$ (6)	\$ (18)	\$ (30)	\$ (42)	\$ (53)	\$ (97)	

Summary

- All inefficiencies have equal impact, so all should be analyzed
- Model can be used for other 'what-if' analysis
 - Is it cost effective to upgrade testers?
 - Is it cost effective to re-buy probe cards?

Run Your Numbers!

Acknowledgments

Joe Foerstel



Manufacturing Engineering – Altera Corporation